

<b>Notice of References Cited</b>	Application/Control No. 09/610,284	Applicant(s)/Patent Under Reexamination BACHLER ET AL	
	Examiner Phylesha L. Dabney	Art Unit 2615	Page 1 of 1

**U.S. PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

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	U	<input type="checkbox"/> Johnson, Robert N; Woods, Stan; "Overview and Status Update for IEEE 1451.2", Presentation at Sensors Expo, 9 May 2000, pages 1-37, (PDF, 172 k). Website: <a href="http://www.telemonitor.com/download.html">http://www.telemonitor.com/download.html</a>
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